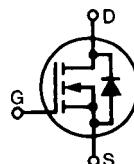


HiPerFET™ Power MOSFETs

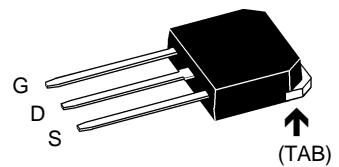
N-Channel Enhancement Mode
High dv/dt, Low t_{rr} , HDMOS™ Family

IXFJ 13N50

V_{DSS} = 500 V
 I_D (cont) = 13 A
 $R_{DS(on)}$ = 0.4 Ω
 t_{rr} ≤ 250 ns



Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	T_J = 25°C to 150°C	500	V	
V_{DGR}	T_J = 25°C to 150°C; $R_{GS} = 1 M\Omega$	500	V	
V_{GS}	Continuous	±20	V	
V_{GSM}	Transient	±30	V	
I_{D25}	T_c = 25°C	13	A	
I_{DM}	T_c = 25°C, pulse width limited by T_{JM}	52	A	
I_{AR}	T_c = 25°C	13	A	
E_{AR}	T_c = 25°C	18	mJ	
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 A/\mu s$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 2 \Omega$	5	V/ns	
P_D	T_c = 25°C	180	W	
T_J		-55 ... +150	°C	
T_{JM}		150	°C	
T_{stg}		-55 ... +150	°C	
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C	
Weight		5	g	



G = Gate, D = Drain,
S = Source, TAB = Drain

Features

- Low profile, high power package
- Long creep and strike distances
- Easy up-grade path for TO-220 designs
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect
- Fast intrinsic Rectifier

Applications

- DC-DC converters
- Synchronous rectification
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control
- Temperature and lighting controls
- Low voltage relays

Advantages

- High power, low profile package
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ C$, unless otherwise specified)	min.	typ.
V_{DSS}	$V_{GS} = 0 V$, $I_D = 250 \mu A$	500		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 2.5 mA$	2		V
I_{GSS}	$V_{GS} = \pm 20 V_{DC}$, $V_{DS} = 0$		±100	nA
I_{DSS}	$V_{DS} = 0.8 \cdot V_{DSS}$ $V_{GS} = 0 V$	$T_J = 25^\circ C$ $T_J = 125^\circ C$	200	μA
$R_{DS(on)}$	$V_{GS} = 10 V$, $I_D = 0.5 \cdot I_{D25}$ Pulse test, $t \leq 300 \mu s$, duty cycle d ≤ 2 %		0.4	Ω

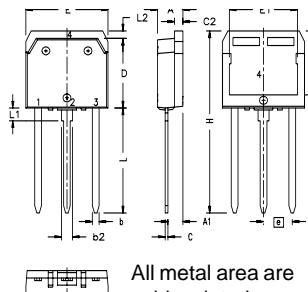
Symbol	Test Conditions	Characteristic Values			
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.	max.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 0.5 I_{D25}$, pulse test	7.5	9.0	S	
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	2800		pF	
		300		pF	
		70		pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 0.5 \cdot I_{D25}, R_G = 4.7 \Omega$ (External)	18	30	ns	
		27	40	ns	
		76	100	ns	
		32	60	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	110	120	nC	
		15	25	nC	
		40	50	nC	
R_{thJC}			0.7	K/W	
R_{thCK}		0.25		K/W	

Source-Drain Diode

(T_J = 25°C, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$		13	A
I_{SM}	Repetitive; pulse width limited by T _{JM}		52	A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V}$, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		1.5	V
t_{rr} Q_{RM} I_{RM}	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$ $I_F = I_s$ $-di/dt = 100 \text{ A}/\mu\text{s}$, $V_R = 100 \text{ V}$	250	ns	
		350	ns	
		0.6		μC
		1.25		μC
		9		A
		15		A

TO-268 Outline



All metal area are solder plated
1 - gate
2 - drain (collector)
3 - source (emitter)
4 - drain (collector)

Dim.	Inches		Millimeters	
	Min	Max	Min	Max
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
b	.045	.057	1.15	1.45
b2	.075	.083	1.90	2.10
C	.016	.026	.040	.065
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
e	.215 BSC		5.45 BSC	
H	1.365	1.395	34.67	35.43
L	.780	.800	19.81	20.32
L1	.079	.091	2.00	2.30
L2	.039	.045	1.00	1.15

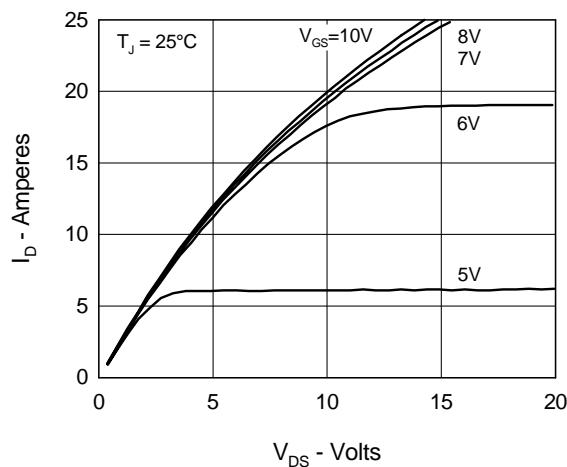
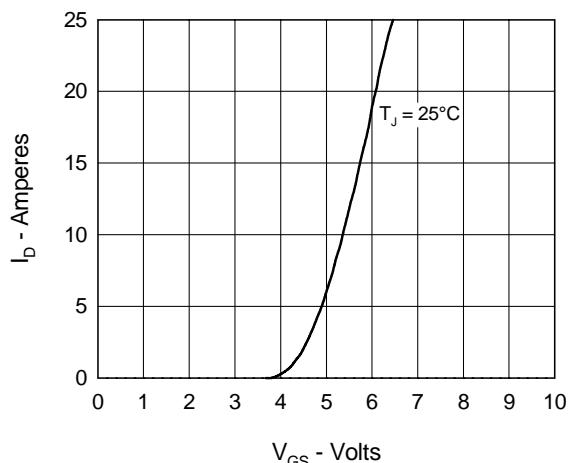
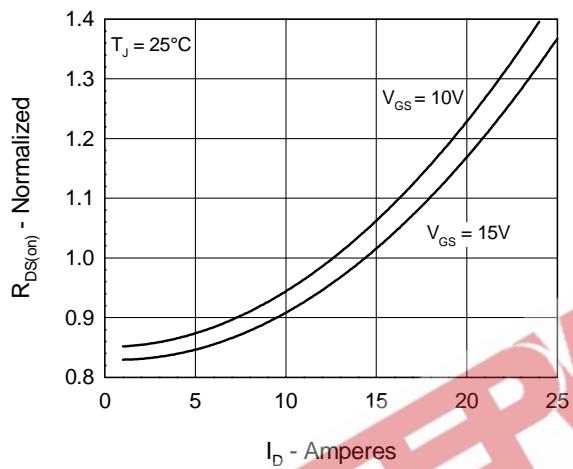
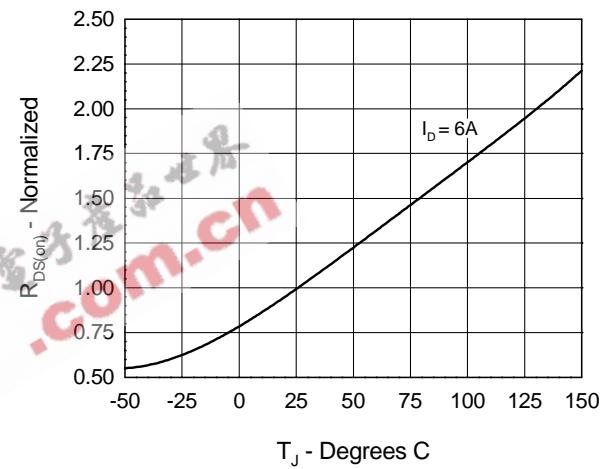
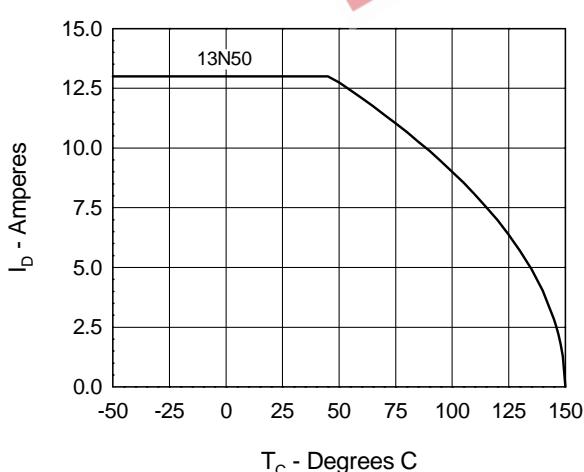
Figure 1. Output Characteristics at 25°C Figure 2. Output Characteristics at 125°C Figure 3. $R_{DS(on)}$ normalized to $0.5 I_{D25}$ valueFigure 4. $R_{DS(on)}$ normalized to $0.5 I_{D25}$ value

Figure 5. Drain Current vs. Case Temperature

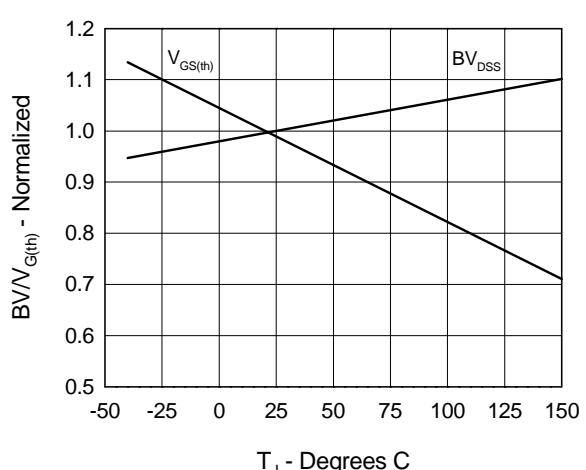


Figure 6. Admittance Curves

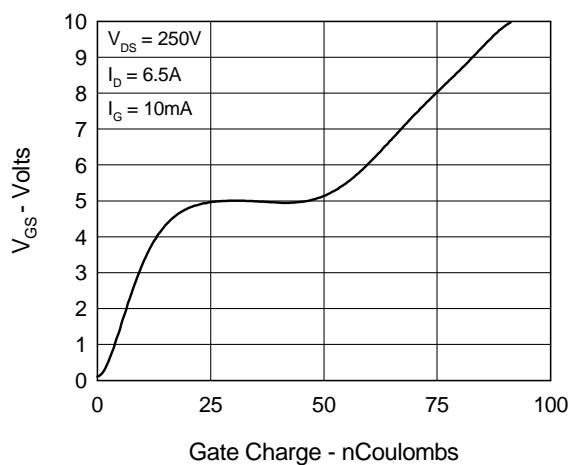


Figure 7. Gate Charge

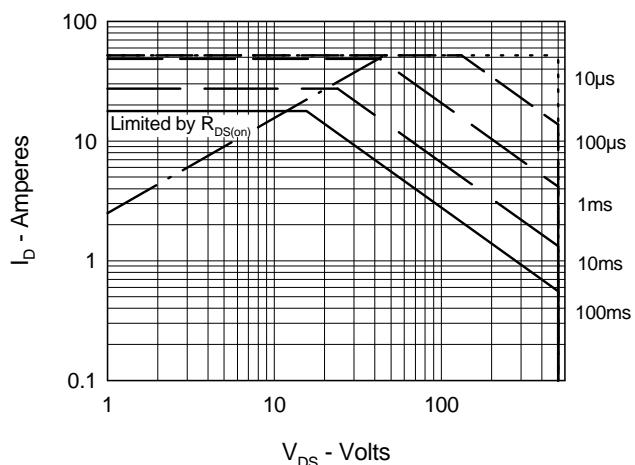


Figure 8. Capacitance Curves

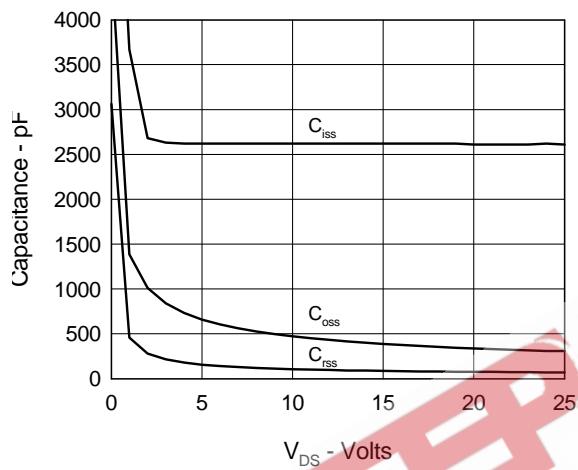


Figure 9. Source Current vs. Source to Drain Voltage

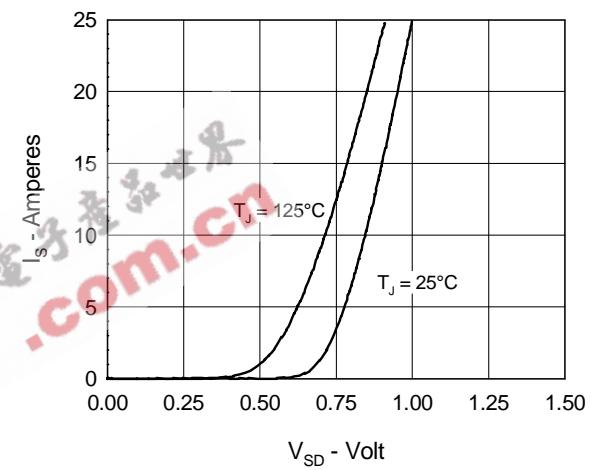


Figure 10. Forward Bias Safe Operating Area

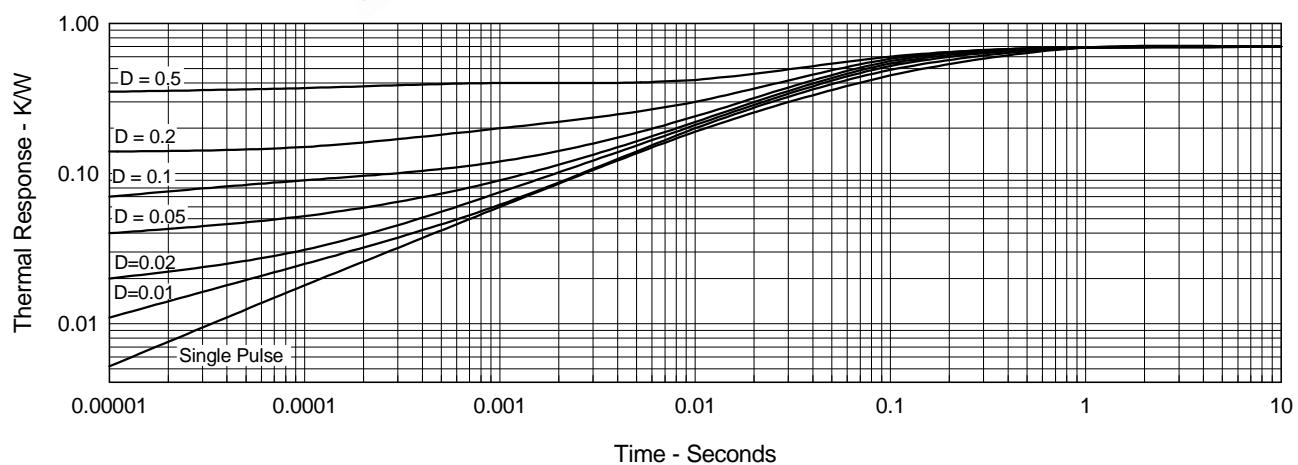


Figure 11. Transient Thermal Resistance